




<p>Searched</p> 	<p>Application/Control No.</p> <p>10750908</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>PINCU ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
700	286,291,297	08/14/2006	HK

U.S. Patent and Trademark Office	Part of Paper No.: 20060814
----------------------------------	-----------------------------

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10750908	PINCU ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
361/58,62,103,104 (consulted Stephen W. Jackson)	06/15/2006	HK
700/286,291,297 (consulted Jayprakash Gandhi and Albert Paladini)	06/15/2006	HK
EAST (US-PGPUB,USPAT,USOCR,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	08/14/2006	HK
U.S. Patent and Trademark Office		Part of Paper No.: 20060814

Interference Searched 	Application/Control No. 10750908	Applicant(s)/Patent Under Reexamination PINCU ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Class	SubClass	Date	Examiner
Interference Search History		08/14/2006	HK
Interference Search History Printout			
U.S. Patent and Trademark Office		Part of Paper No.:	20060814